

Search Notes

Application/Control No.

10/780,039

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

ANDERSON ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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